



**Advanced Power
Electronics Corp.**

AP4409AGM-HF

Halogen-Free Product

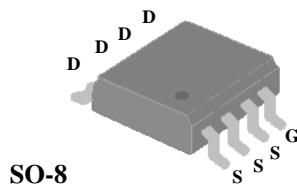
**P-CHANNEL ENHANCEMENT MODE
POWER MOSFET**

▼ Simple Drive Requirement

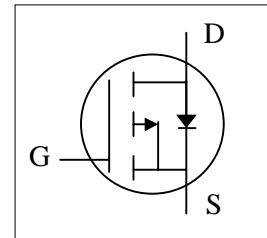
▼ Low On-resistance

▼ Fast Switching Characteristic

▼ RoHS Compliant & Halogen-Free



BV_{DSS}	-30V
$R_{DS(ON)}$	7.2mΩ
I_D	-15A



Description

AP4409A series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The SO-8 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for voltage conversion or switch applications.

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current ³	-15	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current ³	-12	A
I_{DM}	Pulsed Drain Current ¹	-50	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	2.5	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Unit
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient ³	50	°C/W



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-10\text{A}$	-	5.7	7.2	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-7\text{A}$	-	8.3	10.8	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=-250\mu\text{A}$	-1	-1.7	-3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$, $I_{\text{D}}=-10\text{A}$	-	24	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	-10	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_{g}	Total Gate Charge	$I_{\text{D}}=-10\text{A}$	-	50	80	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=-15\text{V}$	-	13	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	23	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=-15\text{V}$	-	14	-	ns
t_{r}	Rise Time	$I_{\text{D}}=-1\text{A}$	-	13	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	82	-	ns
t_{f}	Fall Time	$V_{\text{GS}}=-10\text{V}$	-	48	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	4500	7200	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=-15\text{V}$	-	745	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	685	-	pF
R_{g}	Gate Resistance	f=1.0MHz	-	2.2	4.4	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=-2.1\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=-10\text{A}$, $V_{\text{GS}}=0\text{V}$, $dI/dt=100\text{A}/\mu\text{s}$	-	45	-	ns
			-	33	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board, $t \leq 10\text{s}$; $125^\circ\text{C}/\text{W}$ when mounted on Min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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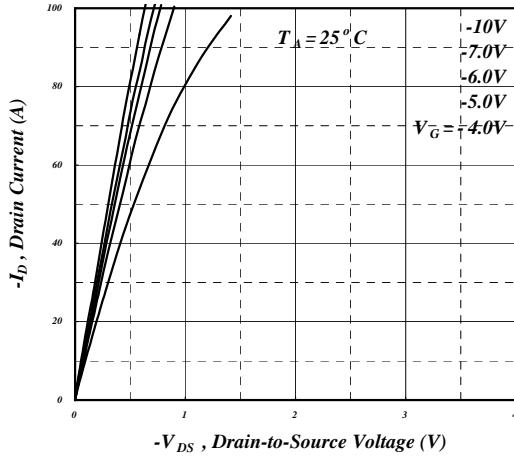


Fig 1. Typical Output Characteristics

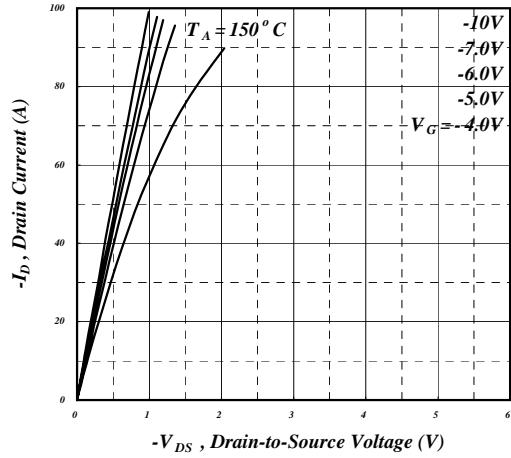


Fig 2. Typical Output Characteristics

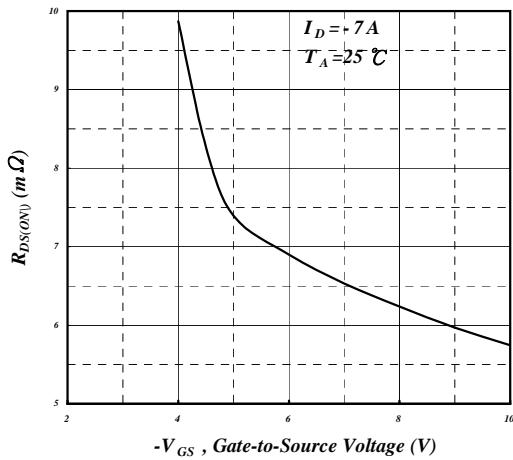


Fig 3. On-Resistance v.s. Gate Voltage

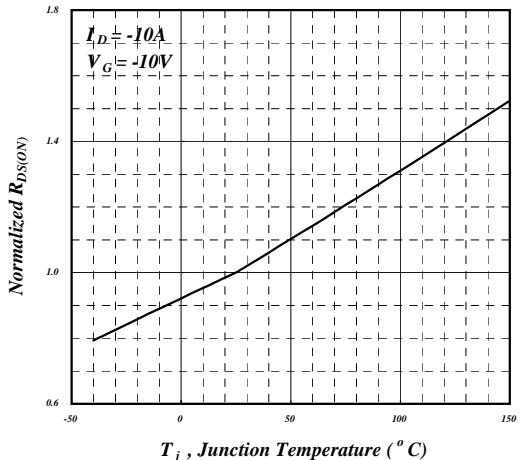


Fig 4. Normalized On-Resistance v.s. Junction Temperature

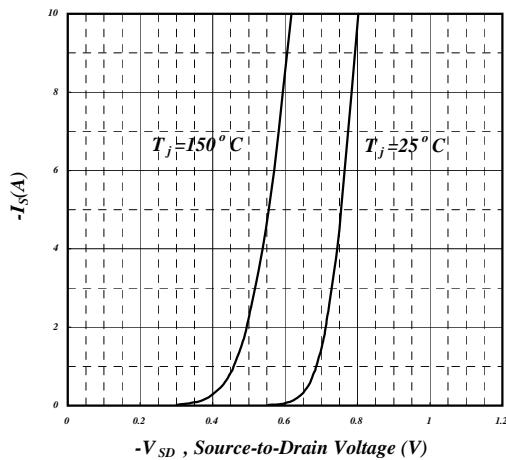


Fig 5. Forward Characteristic of Reverse Diode

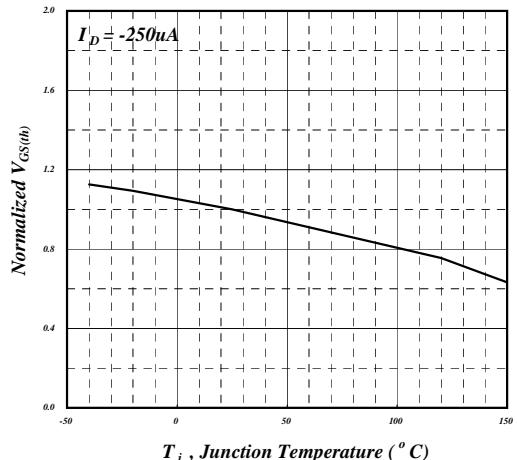


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

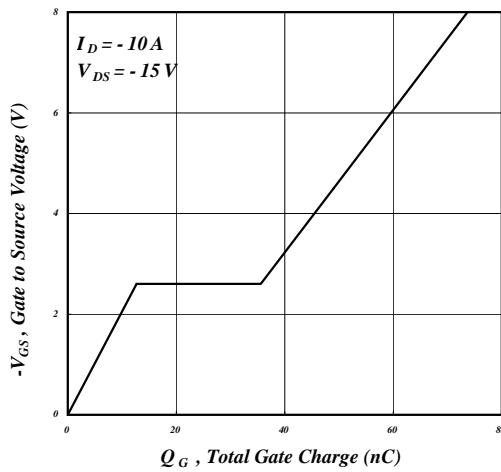


Fig 7. Gate Charge Characteristics

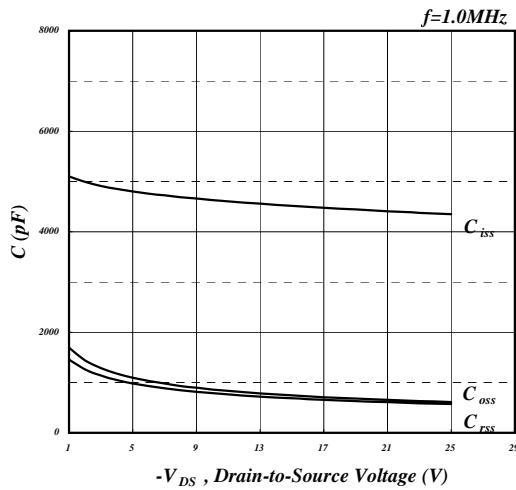


Fig 8. Typical Capacitance Characteristics

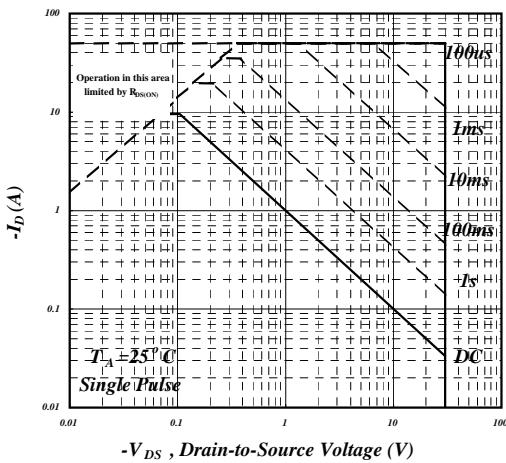


Fig 9. Maximum Safe Operating Area

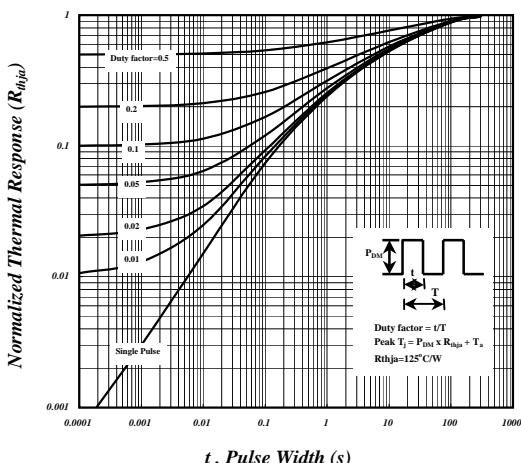


Fig 10. Effective Transient Thermal Impedance

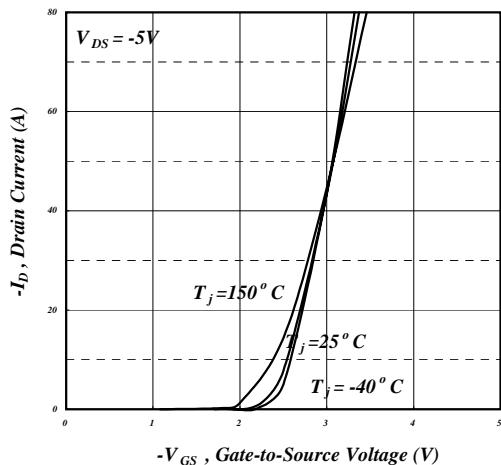


Fig 11. Transfer Characteristics

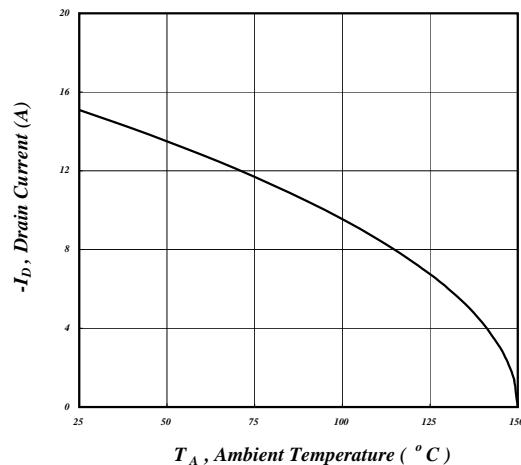


Fig 12. Maximum Continuous Drain Current v.s. Ambient Temperature